5	S	ea	31	C	:h	•	VC	te	es	
II	II	III				Ш	Ш	MII		11

Application/Control No.	Applicant(s)/Patent under Reexamination			
10/791,391	CHAN ET AL.			
Examiner	Art Unit			
Fisa R Flhilo	1751			

	·			
SEARCHED				
Class	Subclass	Date	Examiner	
-8	405	8/2/2005	EE	
	406	1		
	408			
	410			
	411			
	412			
	421			
	435			
V	585			
132	208			
424	70.1	J	J	

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
		-				
	•					

SEARCH NO (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
East .	8/2/2005	EE
Inventor name search	8/2/2005	EE
	·	